Search Notes

Applic	ation/Control No.	Applicant(s)/Patent under Reexamination	
10/773	,800	FAN, YUAN-HENG	
Exami	ner	Art Unit	
Granvi	II D. Lee Jr	2891	

SEARCHED					
JERIOTED					
Class	Subclass	Date	Examiner		
438	612-618	4/27/2005	GL		
438	455,652	4/27/2005	GL		
438	15,25,67	4/27/2005	GL		
438	106-108	4/27/2005	GL		
257	734-738	4/27/2005	GL		
257	780-781	4/27/2005	GL		
257	784	4/27/2005	GL		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See East	4/27/2005	GL		
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